

**Search Notes**

Application/Control No.

10/064,455

Examiner

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Applicant(s)/Patent under  
Reexamination

HAN, CHIA-HUI

Art Unit

2153

**SEARCHED**

Class	Subclass	Date	Examiner
709	249-250	4/26/2007	SR
719	321, 327	4/27/2007	SR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor and Assignee double patenting search.	4/26/2007	SR
NPL search - IEEE database.	4/26/2007	SR
Consulted w/ Primary Examiner Beatriz Prieto 2142; search strategy	4/26/2007	SR
Consulted w/ Primary Examiner Van Nguyen Class 719, AU 2194; allowable subject matter	4/27/2007	SR